

PERFORMANCE SPECIFICATION
 RESISTORS, FIXED, FILM, HIGH VOLTAGE
 GENERAL SPECIFICATION FOR

This amendment forms a part of MIL-PRF-49462A, dated 15 March 1991, and is approved for use by all Departments and Agencies of the Department of Defense.

PAGE 2

2.1.1, SPECIFICATIONS, MILITARY: Delete "MIL-STD-45662 - Calibration Systems Requirements."

2.2: Add the following:

"AMERICAN NATIONAL STANDARDS INSTITUTE (ANSI)

ANSI/NCSL Z540-1 - Calibration Laboratory and Measuring and Test Equipment, General Requirements for.

"INTERNATIONAL ORGANIZATION FOR STANDARDS (ISO)

ISO 10012-1 - Quality Assurance Requirements for Measuring Equipment, Part 1: Meteorological Confirmation System for Measuring Equipment.

"(Application for copies should be addressed to the American National Standards Institute, 11 West 42nd Street, New York, NY 10036)."

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TABLE I, maximum resistance row: Delete and substitute:

Maximum resistance temperature characteristic (RTC) percent/°C part/million/°C	For R < 500 MΩ RTC ≤ 200 ppm	For R < 500 MΩ RTC ≤ 200 ppm	For R < 500 MΩ RTC ≤ 200 ppm	For R < 500 MΩ RTC ≤ 200 ppm
	For R ≥ 500 MΩ RTC ≤ 500 ppm	For R ≥ 500 MΩ RTC ≤ 500 ppm	For R ≥ 500 MΩ RTC ≤ 500 ppm	For R ≥ 500 MΩ RTC ≤ 500 ppm

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3.16: Delete and substitute:

"3.16 Moisture resistance When resistors are tested as specified in 4.16, there shall be no evidence of mechanical damage. The change in resistance between initial measurement and final measurements shall not exceed ± 0.5 percent. In addition, the dielectric withstanding voltage shall be as specified in 3.14, and insulation resistance shall be 100 megohms, minimum."

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4.1.2: Delete and substitute:

"4.1.2 Test equipment and inspection facilities. The supplier shall establish and maintain a calibration system in accordance with ANSI/NCSL Z540-1, ISO-10012-1, or equivalent system as approved by the qualifying activity."

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4.5.1.1: Delete and substitute:

"4.5.1.1 Inspection and production lot

"4.5.1.1.1 Inspection lot An inspection lot, as far as practicable, shall consist of all resistors of the same style, characteristic, and protective enclosure or coating produced in a period not to exceed 30 days, produced under essentially the same conditions and offered for inspection at one time.

"4.5.1.1.2 Production lot. A production lot shall consist of all resistors of the same characteristic, style, nominal resistance value, and resistance tolerance. Manufacture of all parts in the lot shall have been started, processed, assembled, and tested as a group. Lot identity shall be maintained throughout the manufacturing process."

4.5.1.2.1.1, line 1: Between "on" and "100" add "a production lot basis on".

PAGE 16

TABLE VIII, solderability row: Delete.

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* 4.17, life: Delete "106" and substitute "108".

* 4.17c: Delete and substitute:

"c. Initial measurement: DC resistance shall be measured at room temperature which shall be used as the reference reading for all subsequent measurements under the same conditions."

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4.17f: Delete and substitute:

"f. Measurement during test: DC resistance shall be measured at the end of the 15-minute off periods, after, 250 +72, -24; 500 +72, -24; 1,000 +72, -24 hours have elapsed. Measurement shall be made as near as possible to the specified time but may be adjusted so that measurement need not be made during other than normal workdays. "

The margins of this amendment are marked with an asterisk to indicate where changes (additions, modifications, corrections, deletions) from the previous amendment were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the notations and relationship to the last previous amendment.

Custodians:

Army - CR
Navy - EC
Air Force - 85

Preparing activity:
DLA - CC

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Review activities:

Army - AR, AT, AV, CR4, MI
Navy - AS, CG, MC, OS
Air Force - 17, 19
NASA - NA